

Notice of References Cited	Application/Control No. 10/684,759	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Alyssa M. Alter	Art Unit 3762	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,360,123 B1	03-2002	Kimchi et al.	600/547
*	B	US-2004/0172080 A1	09-2004	Stadler et al.	607/017
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Merriam-Webster Online Dictionary, www.webster.com, defined: metric.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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